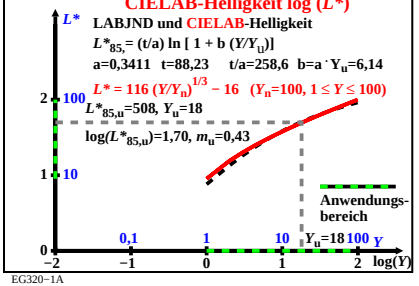
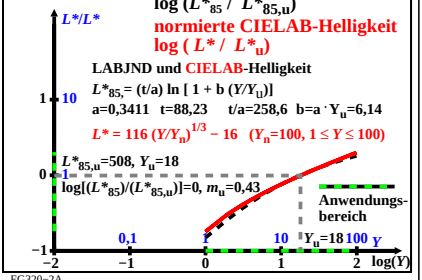
log (L^*) LABJND-Helligkeit log (0,1L^*_{85}) CIELAB-Helligkeit log (L^*)



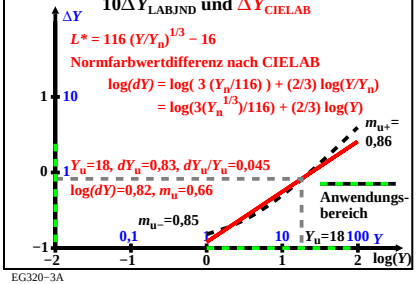
EG320−1A

log (L^*/L^*_u) normierte LABJND-Helligkeit log (L^*_{85} / $L^*_{85,u}$) normierte CIELAB-Helligkeit log (L^* / L^*_u)



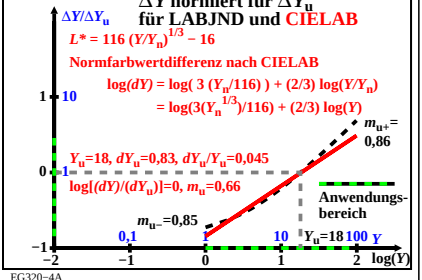
EG320−2A

log ΔY CIE-Normfarbwertdifferenz $10\Delta Y_{LABJND}$ und ΔY_{CIELAB}



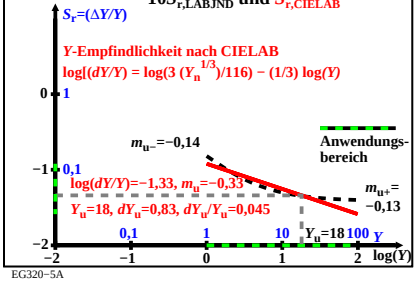
EG320−3A

log($\Delta Y/\Delta Y_u$) CIE-Normfarbwertdifferenz ΔY normiert für ΔY_u für LABJND und CIELAB



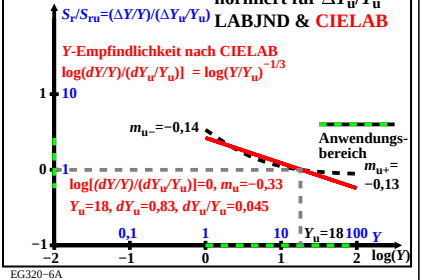
EG320−4A

log ($\Delta Y/Y$) CIE Y-Empfindlichkeit $10S_{r,LABJND}$ und $S_{r,CIELAB}$



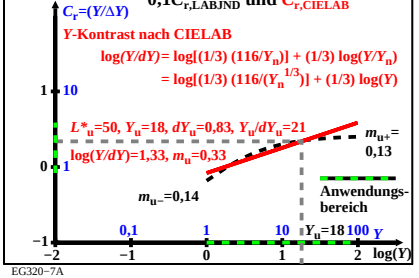
EG320−5A

log [($\Delta Y/Y$) / ($\Delta Y_u/Y_u$)] CIE Y-Empfindlichkeit normiert für $\Delta Y_u/Y_u$ LABJND & CIELAB



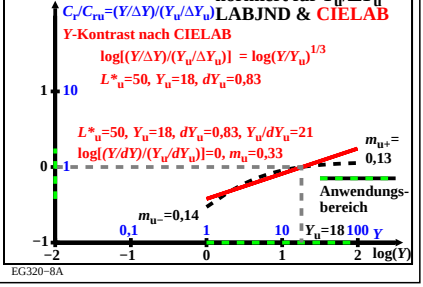
EG320−6A

log ($Y/\Delta Y$) CIE Y-Kontrast $0{,}1C_{r,LABJND}$ und $C_{r,CIELAB}$



EG320−7A

log [($Y/\Delta Y$) / ($Y_u/\Delta Y_u$)] CIE Y-Kontrast normiert für $Y_u/\Delta Y_u$ LABJND & CIELAB



EG320−8A

EG320−7N